


<b>Search Notes</b>  	<b>Application/Control No.</b>  09944424	<b>Applicant(s)/Patent Under Reexamination</b>  FUTAMURA ET AL.
	<b>Examiner</b>  Revak, Christopher A	<b>Art Unit</b>  2131

SEARCHED			
Class	Subclass	Date	Examiner
none	none	6/7/07	CR

SEARCH NOTES		
Search Notes	Date	Examiner
BRS Text Search: USPAT, US PGPUB, USOCR, FPRS, DERWENT, IBM TDB, EPO, JPO (see attached strategy)	6/7/07	CR
Interference Search (see attached strategy)	6/7/07	CR
DIALOG Text Search: COMPSCI, ELECTRON, SOFTWARE (see attached strategy)	6/7/07	CR

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
713	150,155,156,168,175,176,182-186	6/7/07	CR
726	5-7,10,17,19	6/7/07	CR
382	100,115-127	6/7/07	CR